Active Low Noise Terminations: Simulation Approach and Verification

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Introduction

• The equivalent noise temperature Te has a different implication for a 2- or a 1-port network. In the former it is related to the network's noise factor, while in the latter, the equivalent noise temperature is proportional to available noise power from the network. Typically CAD applications are able to compute the first type of equivalent noise temperature but not the second.

- An analytical overview of the noisy behaviour of the circuit is explained representing the two port noisy network through the ABCD representation with two independent noise source (r_a and g_a), a correlation impedance Z, and a noiseless network described in terms of [Z] parameters.
- Two CAD oriented simulation's approaches are presented to allow the circuit performance optimization
- The design of a monolithic active low noise termination realized using the OMMIC ED02AH foundry process is presented
- The measured performance of the monolithic active termination are reported

DESIGN FLOW 3. Simulation 2. Simulation approach-II approach-l 1. Basic theory [S] parameters S_{ih}, N_{ih} $S_{o,b}, N_{o,b}$ AC simulation provides simulation provides e, that allows to compute F_b and allows to $P_{Z_0} = \frac{|e_n|^2}{Z}$ Noiseles compute Gav P20 (noise power delivered Network to Z01 T=0 Equivalent noise [Z(m)] P., is computed temperature is $P_{av} = \frac{P_{Z_0}}{1 - |\Gamma_{u}|^2}$ knowing the input obtained $V_{in} = r_n + g_n z_{11} + \frac{z_{12} (e_L + g_n z_{21})}{Z_I + z_{22}}$ reflection coefficient $F_b = \frac{S_{i,b}/N_{i,b}}{S_{o,b}/N_{o,b}} \longrightarrow N_{o,b} = N_{i,b}F_b \frac{S_{o,b}}{S_{i,b}} = N_{i,b}F_b G_{av,b}$ Equivalent noise $T_e = \frac{P_{Z_0}}{k_B B \left(1 - \left|\Gamma_{in}\right|^2\right)}$ temperature is obtained $T_{e} = \frac{N_{o,b}}{k_{o}B} = k_{B}T_{0}B\frac{F_{b}G_{av,b}}{k_{o}B} = T_{0}G_{av,b}F_{b}$ $|V_{in}|^2 = |r_n|^2 + f([Z(\omega)])|Z_{in} - Z_{y}|^2 |g_n|^2$ **Required DATAs:** $T_e = \frac{P_{av}}{k_B B} = \frac{\left|V_{in}\right|^2}{4 \operatorname{Re}[Zin]k_B B}$ Reverse available gain (function of Z_i) Reverse noise factor (function of Z_i) T = 0KS parameter simulations combined $T_e = \frac{\left|r_n\right|^2 + f\left(\left[Z(\omega)\right]\right)\left|Z_{in} - Z_{\gamma}\right|^2 \left|g_n\right|^2}{4\operatorname{Re}[Z_{in}]k_B B}$ with reverse device noise factor **Required DATAs:** computation • Input reflection coefficient (function of Z_l) Analytic derivation of the equivalent Root mean square of the noise voltage (en) @ node n (function of Z_{L}) noise temperature starting from the 4 6. Applications & noise parameters of the 2-port active AC simulations considering a noiseless input network termination conclusions 5. Measurements 4. Design Two possible application scenarios are introduced: Schematic Micro-photo Eauivalent Noise

Temperature versus

frequency and bias

condition $(V_{dd}(V), I_d)$

50 Ohm matching

bias condition

versus frequency and

(mA))

In the field of noise model extraction, using the F50 method and the proposed termination, it is possible to obtain an increased accuracy compared to the standard F50 method

In the field of antenna arrays, where the proposed circuit could be used as dummy load in the arrays, allowing to lower the overall equivalent noise temperature of the system without affecting the symmetry of the antenna system

Conclusions and further developments

Further circuit optimization should be directed toward a reduction in the terminating impedance variation (as function of the bias voltage) and toward an higher temperature variation range to allow the usability as a two state noise source.



MMIC information:

Single bias voltage

process (GaAs 0.18um)

OMMIC ED02AH foundry

(full C band)



Measurements of the full C-band active termination